## swissbit®

**Product Fact Sheet** 

**Industrial** M.2 PCle SSD

N-30m2 Series PCle 3.1, 3D TLC

Industrial Temperature Grade

February 23, 2023 1.01 Date:

Revision:





## **Product Summary**

- Capacities: 240 GBytes, 480 GBytes, 960 GBytes, 1920 GBytes, 3840 GBytes
- Form Factor: PCI Express M.2 2242/2280 (42/80 mm x 22 mm x 3.8 mm)
- Compliance<sup>1</sup>: PCI Express (PCIe) Base Specification Revision 3.1
- Interface: Gen3 x 4 Lanes
  - o Drive operates in x1 mode in x1 M.2 PCle slots
  - o Drive operates in x2 mode in x2 M.2 PCle slots
  - Drive operates in x4 mode in x4 M.2 PCle slots
- Command Sets: Supports NVMe 1.4
- Target Performance:
  - Read Performance: Sequential Read up to 3,510 MBytes/s, Random Read 4K up to 475,900 IOPS
  - Write Performance: Sequential Write up to 3,110 MBytes/s, Random Write 4K up to 520,000 IOPS
- Operating Temperature Range<sup>2</sup>:
  - o Industrial: -40 °C to 85 °C
- Storage Temperature Range: -40 °C to 85 °C
- Power:
  - Power States PSo, PS1, PS2, PS3 and PS4
  - Thermal Throttling supported
- Data Retention<sup>3</sup>: 10 Years @ Life Begin; 1 Year @ Life End, @40°C
- **Shock/Vibration:** 1,500 *g* | 50 *g*
- High-Performance Processor with Integrated, Parallel Flash Interface Engines:
  - Triple-Level Cell (TLC) 3D NAND Flash
  - DDR4 DRAM based Controller architecture
  - o 240 bit LDPC correction per 2 kByte
- · High Reliability:
  - Mean Time Between Failure (MTBF): > 3,000,000 hours
  - o Data Reliability: < 1 non-recoverable error per 10<sup>16</sup> bits read

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<sup>&</sup>lt;sup>1</sup> To check the compatibility of the customer system and the storage device is part of the customer's responsibility. Swissbit can provide guidance and support on request.

<sup>&</sup>lt;sup>2</sup> Adequate airflow is required to ensure the temperature, as reported in the S.M.A.R.T. data, does not exceed 125°C (industrial temperature drive).

NAND Flash suppliers refer to JEDEC JESD47 and JESD22 for Data Retention testing. Based on the information provided by the NAND Flash suppliers, Data Retention is targeted as shown